

X-RAY ABSORPTION STUDIES OF LOCAL STRUCTURE WITH FEMTOMETER ACCURACY

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In the last years, the XAFS experimental techniques have undergone remarkable developments: (i) experiments with unprecedented accuracy and under extreme conditions of high pressure and temperature [1], (ii) experiments with nanoscale lateral resolution [2], that were not even conceivable just a few years ago, can nowadays be performed. New applications, stimulated by accurate experimental temperature-dependent XAFS measurements on Ge, ReO₃ and SrFe_xTi_{1-x}O₃, can be carried out. In parallel with the experimental techniques, XAFS theory and data analysis have made considerable progress. Femtometer accuracy in the determination of interatomic distances is now attainable [1, 2]. Therefore, new effects can be studied with femtometer accuracy, for example:

- isotopic effect on EXAFS and isotopic effect on the lattice dynamics and anharmonic properties of Ge⁷⁰ and Ge⁷⁶ (see [1] and Highlight ESRF 2008);
- materials with negative thermal expansion as ReO₃, AgO₂, etc. (see [3] and Highlight ESRF 2006);
- materials with Jahn-Teller (JT) effect, small radium polaron (WO₃) or with charge disproportionation as SrFe_xTi_{1-x}O₃ (see [4] and Highlight ESRF 2007);
- Solid solutions as SrFe_xTi_{1-x}O₃, Th_{1-x}U_xO₂ etc. (see [4,5] and Highlight ESRF 2007).

References

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